

MB8279RT-20/-25

CMOS 72K-BIT HIGH-SPEED SRAM

8K Words x 9 Bits Synchronous CMOS Static Random Access Memory with Automatic Power Down

The Fujitsu MB8279RT is a 8,192 words x 9 bits static random access memory fabricated with a CMOS silicon gate process.

Write operation is initiated by an internal write pulse generator, which is driven by the CLK input; therefore, external control of write pulse width is not necessary. Compared to the traditional RAM, the MB8279RT provides improved system level cycle time because signal skews are not involved.

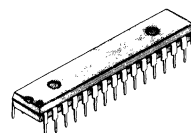
The MB8279RT is housed in 32-pin plastic skinny DIP and SOP packages. All pins are TTL compatible and a single +5 V power supply is required.

- Organization: 8,192 words x 9 bits
- Access time: $t_{ACL} = 20$ ns max. (MB8279RT-20)
 $t_{ACS2} = t_{PE2} = 10$ ns max.
 $t_{ACL} = 25$ ns max. (MB8279RT-25)
 $t_{ACS2} = t_{PE2} = 12$ ns max.
- Registered addresses, CS_1 , WE and data inputs
- Write cancel function by asynchronous CS_2 pin
- On-chip write pulse generator
- On-chip parity checker
- CMOS peripheral circuits
- Single +5 V power supply $\pm 10\%$ tolerance with low current drain:
120 mA max. Active operation
30 mA max. Standby operation
- Common data inputs and outputs
- TTL compatible inputs and outputs
- Three-state data outputs and open drain parity error outputs
- Standard 32-pin Plastic Packages:
Skinny DIP (300 mil) MB8279RT-xxPSK
SOP MB8279RT-xxPF

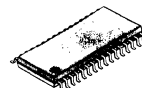
Absolute Maximum Ratings (See Note)

Rating	Symbol	Value	Unit
Supply Voltage	V_{CC}	-0.5 to +7.0	V
Input Voltage	V_{IN}	-3.5 to +7.0	V
Output Voltage	V_{IO}	-0.5 to +7.0	V
Output Current	I_{OUT}	± 20	mA
Power Dissipation	P_D	1.0	W
Temperature Under Bias	T_{BIAS}	-10 to +85	°C
Storage Temperature Range	T_{STG}	-40 to +125	°C

Note: Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

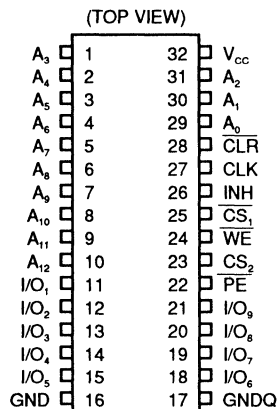


PLASTIC PACKAGE
DIP-32P-M02



PLASTIC PACKAGE
FPT-32P-M02

PIN ASSIGNMENT



This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high impedance circuit.

Fig. 1 – MB8279RT BLOCK DIAGRAM

The block diagram illustrates the internal architecture of the MB8279RT chip. It features an ADDRESS REGISTER (12-bit) and a CONTROL REGISTER (3-bit) that interface with the ROW DECODER and the 256 x 32 x 9 MEMORY CELL ARRAY. The MEMORY CELL ARRAY is connected to the I/O GATE & COLUMN DECODER. The I/O GATE & COLUMN DECODER is connected to the DIN REGISTER & I/O BUFFER, which provides 16 I/O lines (I/O₀ to I/O₁₅). The DIN REGISTER & I/O BUFFER is also connected to the PARITY CHECK block. The CONTROL REGISTER is connected to the WRITE PULSE GENERATOR, which provides a write pulse to the DIN REGISTER & I/O BUFFER. The WRITE PULSE GENERATOR is also connected to the CONTROL BUFFER, which provides a control signal to the DIN REGISTER & I/O BUFFER. The CONTROL BUFFER is connected to the PARITY CHECK block. The PARITY CHECK block provides a parity output (PE). The chip is powered by V_{CC}, GNDQ, and GND.

Legend:

- V_{CC}
- GNDQ
- GND

Parameter	Symbol	Min	Typ	Max	Unit
I/O Capacitance ($V_{IO}=0V$)	C_{IO}			8	pF
Input Capacitance ($V_{IN}=0V$)	C_{IN}			6	pF

PIN DESCRIPTION

Symbol	Pin name	Input/Output	Function
CLK	Clock	Input	Address, $\overline{CS}_1$, and $\overline{WE}$ are fetched at the rising edge of the CLK, and D_{in} is fetched at falling edge of the CLK.
INH	Inhibit	Input	While INH="H", a low level of CLK is disabled.
$\overline{CLR}$	Clear	Input	When $\overline{CLR}$ ="L", the contents of $\overline{CS}_1$ and $\overline{WE}$ register are cleared to standby.
A_0 to A_{12}	Address Input	Input	Synchronous address inputs.
$\overline{CS}_1$	Chip Select 1	Input	Synchronous Chip Select 1 ($\overline{CS}_1$) input. (This pin can be used as power down.)
CS_2	Chip Select 2	Input	Asynchronous high-speed Chip Select 2 (CS_2) input. (This pin can be used as write cancel.)
$\overline{WE}$	Write Enable	Input	Synchronous Write Enable ($\overline{WE}$) input.
I/O ₁ to I/O ₉	Data Input/Output	Input/Output	Data inputs/outputs. (Synchronous data input/Asynchronous data outputs)
PE	Parity Error	Output	Asynchronous parity error output: $\overline{PE}$ output remains High-Impedance state through undefined area.
V_{CC}	Power Supply	—	+5V $\pm$ 10% power supply.
GNDQ	Ground for Output	—	Ground for output circuits.
GND	Ground for Others	—	Ground for other circuits.

TRUTH TABLE

$\overline{CLR}$	$\overline{CS}_1$	CS_2	$\overline{WE}$	MODE	I/O PIN	$\overline{PE}$ OUTPUT PIN	SUPPLY CURRENT
L	X	X	X	STANDBY	HIGH-Z	HIGH-Z	STANDBY
H	H	X	X	STANDBY	HIGH-Z	HIGH-Z	STANDBY
H	L	L	X	CHIP DISABLE	HIGH-Z	HIGH-Z	ACTIVE
H	L	H	H	READ	D_{OUT}	$\overline{PE}$ OUTPUT	ACTIVE
H	L	H	L	WRITE	D_{IN}	HIGH-Z	ACTIVE

Legend: H=High level, L=Low level, X=Don't care.

Notes: $\overline{CS}_1$, and $\overline{WE}$ are input at the rising edge of the CLK.

$\overline{PE}$ output remains High-Impedance state through undefined area.

RECOMMENDED OPERATING CONDITIONS

(Referenced to GND)

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V_{CC}	4.5	5.0	5.5	V
Ambient Temperature	T_A	0		70	°C

DC CHARACTERISTICS

(Recommended operating conditions otherwise noted)

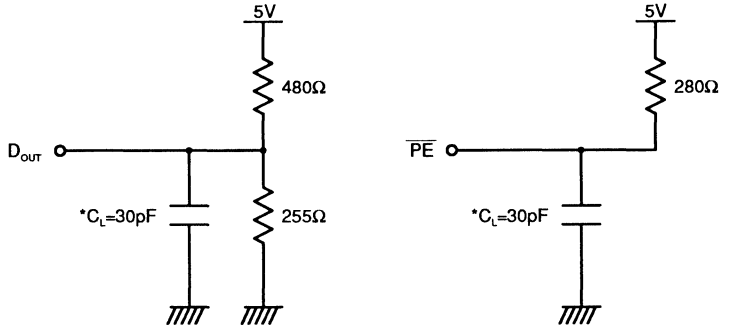
Parameter	Test Conditions	Symbol	Min	Max	Unit
Standby Supply Current	$\overline{CS}_1 = V_{IH}$	I_{SB}		30	mA
Operating Supply Current	$\overline{CS}_1 = V_{IL}$, I/O=Open Cycle=min.	I_{CC}		120	mA
Input Leakage Current	$V_{IN} = \text{GND to } V_{CC}$	I_{IL}	-10	10	μA
Output Leakage Current	$\overline{CS}_1 = V_{IH}$, or $CS_2 = V_{IL}$ $V_{OUT} = \text{GND to } V_{CC}$	I_{LVO}	-10	10	μA
Input Low Voltage		V_{IL}	-2.0*1	0.8	V
Input High Voltage		V_{IH}	2.2	6.0	V
Output High Voltage	$I_{OH} = -4\text{mA}$	V_{OH}	2.4		V
Output Low Voltage	D_{OUT}	$I_{OL} = 8\text{mA}$	V_{OL}	0.4	V
	$\overline{PE}$	$I_{OL} = 16\text{mA}$			
Peak Power-on Current*2	$V_{CC} = \text{GND to } 4.5\text{V}$ $\text{CLR} = \text{GND}$	I_{PO}		120	mA

Note: *1 -2.0V Min. for pulse width less than 20ns. ($V_{IL} = -0.5\text{V}$ at DC level)

*2 The CLR input should be connected to GND to keep the device deselected.

Fig. 2 – AC TEST CONDITIONS

- INPUT PULSE LEVELS: 0.6V TO 2.4V
- INPUT PULSE RISE & FALL TIMES: 5ns (Transient between 0.8V and 2.2V)
- TIMING REFERENCE LEVELS: INPUT: $V_{IL}=0.8V$, $V_{IH}=2.2V$
OUTPUT: $V_{OL}=0.8V$, $V_{OH}=2.2V$
- OUTPUT LOAD



*INCLUDING JIG AND STRAY CAPACITANCE.

($C_L=5pF$ for t_{LZ} , t_{HZ} , t_{LZ2} , t_{HZ2} and t_{CRHZ})

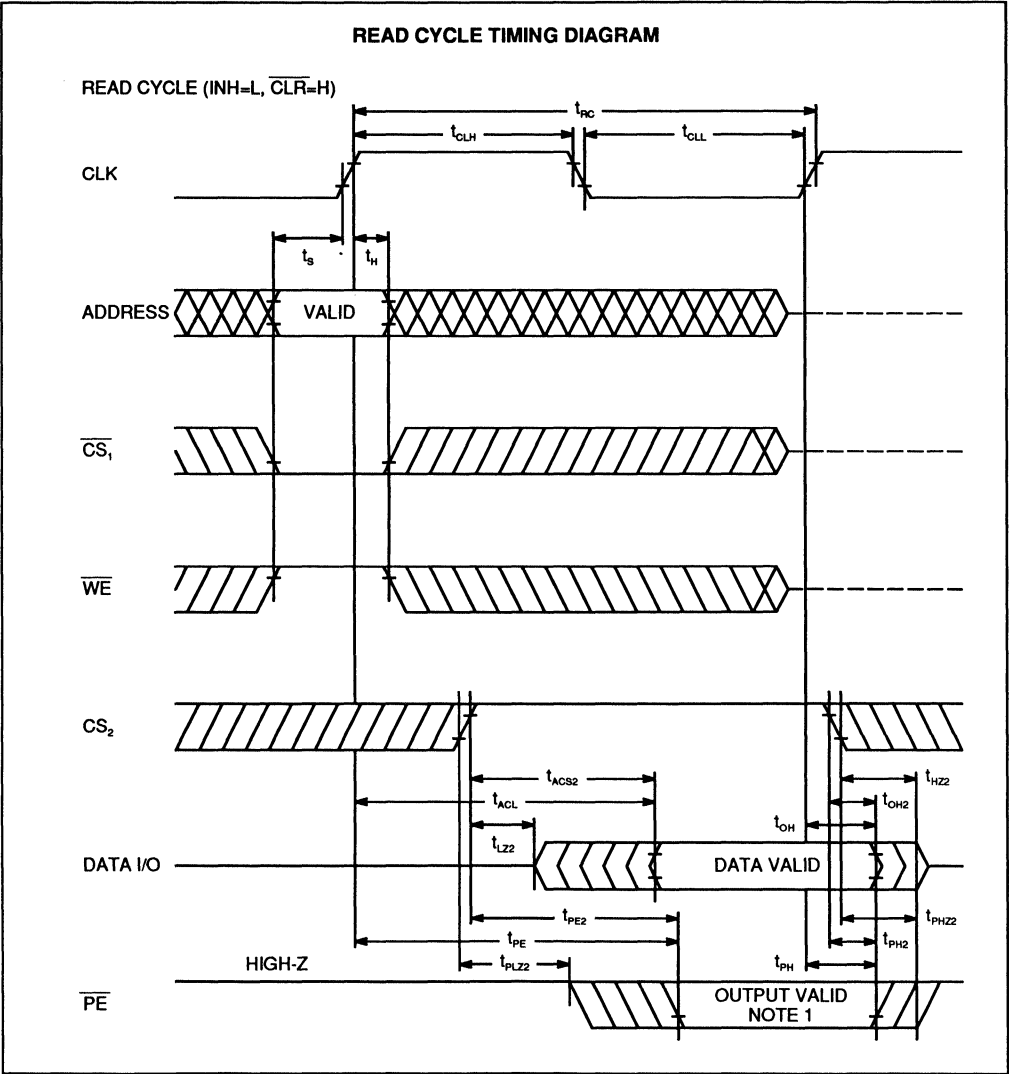
($C_L=5pF$ for t_{PLZ} , t_{PHZ} , t_{PLZ2} , t_{PHZ2} and t_{CRHZ})

AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

READ CYCLE

Parameter		Symbol	MB8279RT-20		MB8279RT-25		Unit
			Min	Max	Min	Max	
Read Cycle Time	When on uses $\overline{PE}$	t_{RC}	20		25		ns
	When uses $\overline{PE}$	t_{RC}	25		30		ns
Clock "H" Level Pulse Width		t_{CLH}	8		10		ns
Clock "L" Level Pulse Width		t_{CLL}	8		10		ns
Input Setup Time		t_S	4		4		ns
Input Hold Time		t_H	2		2		ns
Clock Access Time	D_{OUT}	t_{ACL}		20		25	ns
	$\overline{PE}$	t_{PE}		25		30	ns
CS_2 Access Time	D_{OUT}	t_{ACS2}		10		12	ns
	$\overline{PE}$	t_{PE2}		10		12	ns
CS_2 to Output Low-Z	D_{OUT}	t_{LZ2}	2		2		ns
	$\overline{PE}$	t_{PLZ2}	2		2		ns
CS_2 to Output High-Z	D_{OUT}	t_{HZ2}	2	8	2	10	ns
	$\overline{PE}$	t_{PHZ2}	2	8	2	10	ns
Output Hold from Clock	D_{OUT}	t_{OH}	2		2		ns
	$\overline{PE}$	t_{PH}	2		2		ns
Output Hold from CS_2	D_{OUT}	t_{OH2}	2		2		ns
	$\overline{PE}$	t_{PH2}	2		2		ns



WRITE CYCLE

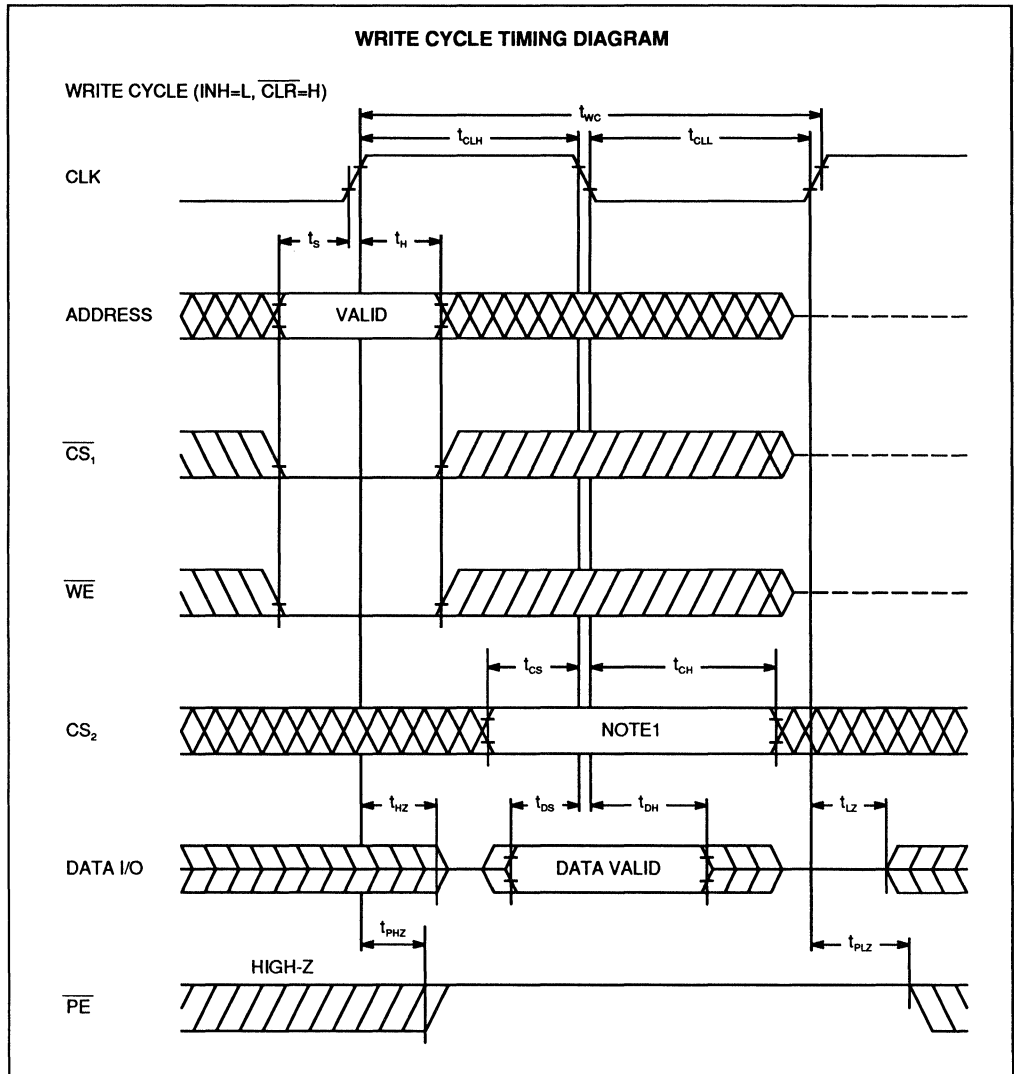
Parameter		Symbol	MB8279RT-20		MB8279RT-25		Unit
			Min	Max	Min	Max	
Write Cycle Time		t_{WC}	20		25		ns
Clock "H" Level Pulse Width		t_{CLH}	8		10		ns
Clock "L" Level Pulse Width		t_{CLL}	8		10		ns
Input Setup Time		t_s	4		4		ns
Input Hold Time		t_h	2		2		ns
CS ₂ Setup Time		t_{CS}	2		2		ns
CS ₂ Hold Time		t_{CH}	8		10		ns
Data Setup Time		t_{DS}	0		0		ns
Data Hold Time		t_{DH}	6		6		ns
CLK to Output High-Z	D _{OUT}	t_{HZ}	2	8	2	10	ns
	$\overline{PE}$	t_{PHZ}	2	8	2	10	ns
CLK to Output Low-Z	D _{OUT}	t_{LZ}	2		2		ns
	$\overline{PE}$	t_{PLZ}	2		2		ns

CLOCK INHIBIT TIMING

Parameter		Symbol	MB8279RT-20		MB8279RT-25		Unit
			Min	Max	Min	Max	
Clock Inhibit Setup Time		t_{CLIS}	2		2		ns
Clock Inhibit Hold Time		t_{CLIH}	2		2		ns
Clock Enable Setup Time		t_{CLES}	2		2		ns
Clock Enable Hold Time		t_{CLEH}	0		0		ns

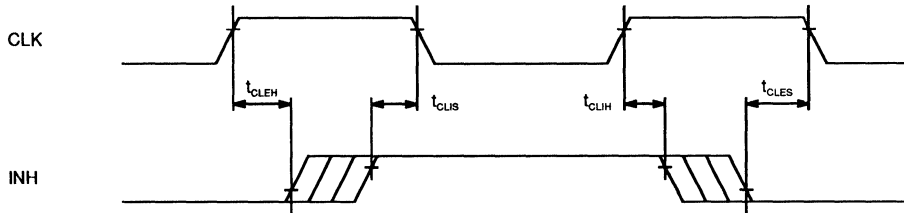
REGISTER CLEAR TIMING

Parameter		Symbol	MB8279RT-20		MB8279RT-25		Unit
			Min	Max	Min	Max	
Clear Pulse Width		t_{CRW}	7		7		ns
Clear Hold Time		t_{CRH}	10		10		ns
Clear Recovery Time		t_{CRR}	10		10		ns
Clear to Output High-Z		t_{CRHZ}	2	8	2	10	ns



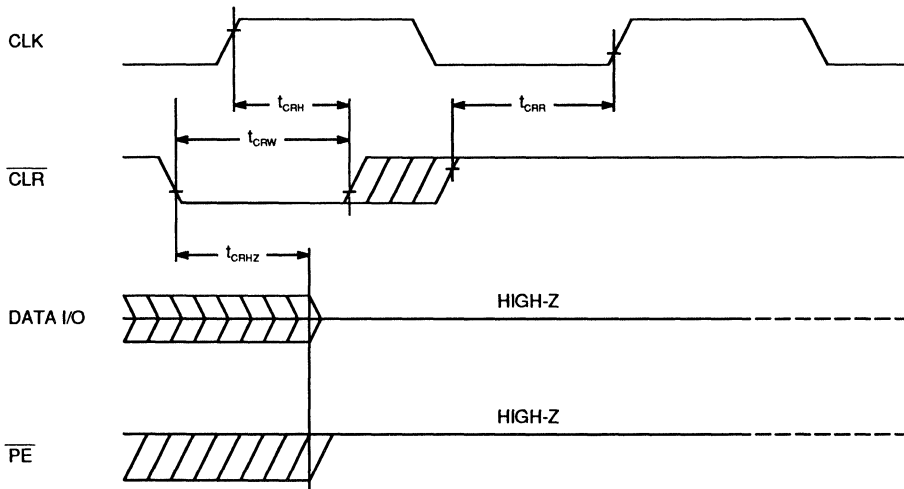
CLOCK INHIBIT TIMING DIAGRAM

CLOCK INHIBIT

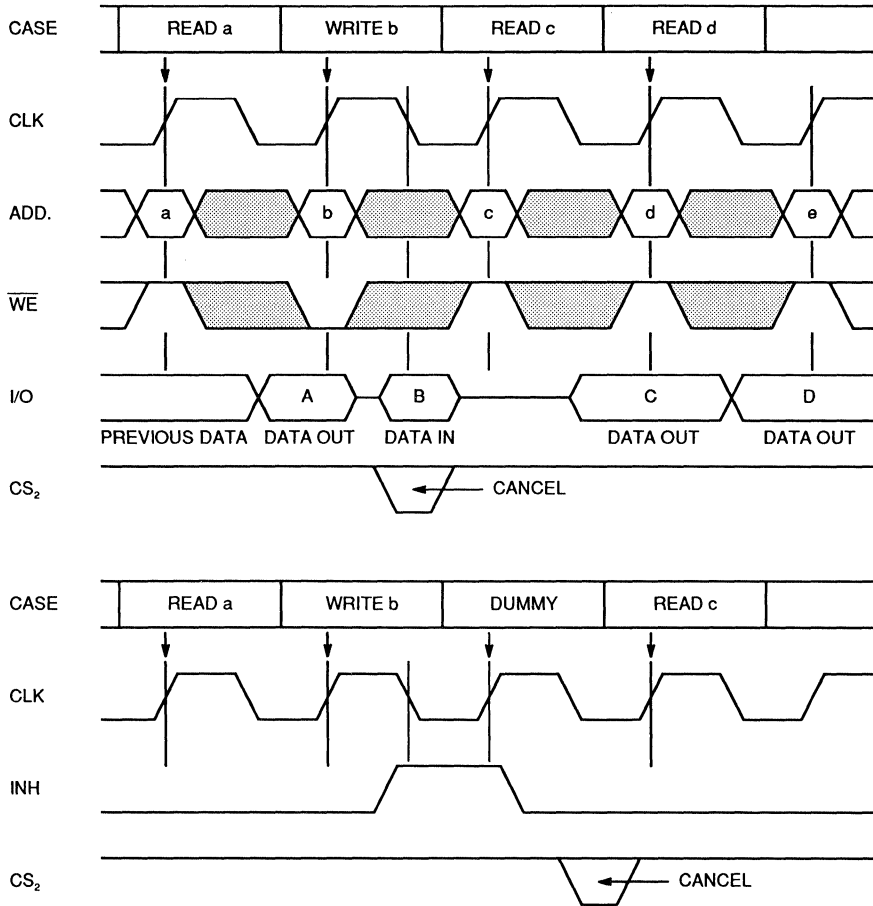


REGISTER CLEAR TIMING

REGISTER CLEAR

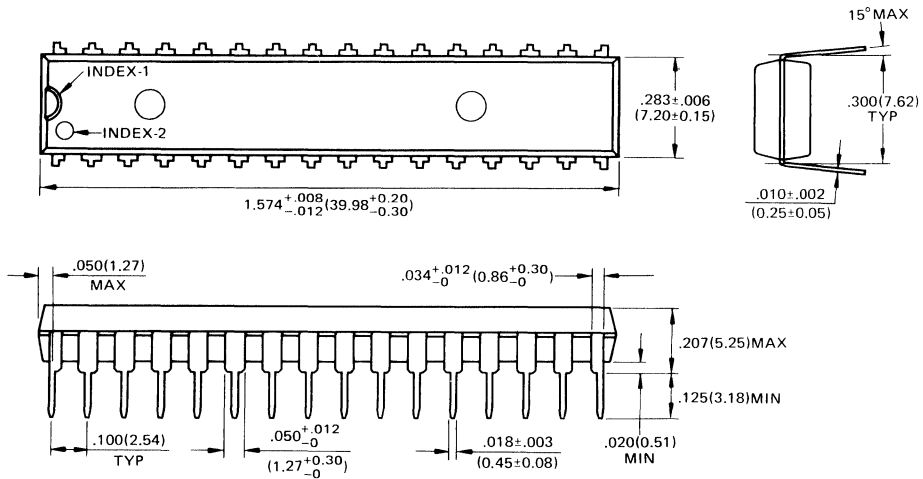


EXAMPLE OF MB8279RT BASIC FUNCTION



PACKAGE DIMENSIONS

32-LEAD PLASTIC DUAL IN-LINE PACKAGE
(CASE No.: DIP-32P-M02)



Dimensions in
inches (millimeters)

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PACKAGE DIMENSIONS (Continued)

